Search Notes



| Application/Control N | 0 |
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TAKAHASHI ET AL.

Reexamination

Applicant(s)/Patent Under

Examiner

Loewe, Sun Jae Y

Art Unit

1626

SEARCHED

| Class | Subclass | Date | Examiner |
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SEARCH NOTES

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| restriction requirement | 1-4-2008 | sl |

INTERFERENCE SEARCH

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